INTEGRATED CIRCUITS

DATA SHEET

74F27Triple 3-input NOR gate

Product specification

1991 Feb 05

IC15 Data Handbook





Triple 3-input NOR gate

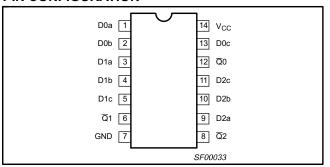
74F27

FEATURE

• Industrial temperature range available (-40°C to +85°C)

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F27	3.0ns	6.5mA

PIN CONFIGURATION



ORDERING INFORMATION

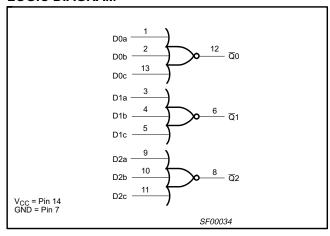
	C	ORDER CODE	
DESCRIPTION	COMMERCIAL RANGE V_{CC} = 5V ±10%, T_{amb} = 0°C to +70°C	INDUSTRIAL RANGE V _{CC} = 5V ±10%, T _{amb} = −40°C to +85°C	PKG DWG #
14-pin plastic DIP	N74F27N	174F27N	SOT27-1
14-pin plastic SO	N74F27D	174F27D	SOT108-1

INPUT AND OUTPUT LOADING AND FAN OUT TABLE

PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
Dna, Dnb, Dnc	Data inputs	1.0/1.0	20μA/0.6mA
Qn	Data output	50/33	1.0mA/20mA

NOTE: One (1.0) FAST unit load is defined as: $20\mu A$ in the high state and 0.6mA in the low state.

LOGIC DIAGRAM



FUNCTION TABLE

	INPUTS		OUTPUT
Dna	Dnb	Dnc	Q n
L	L	L	Н
Х	Х	Н	L
Х	Н	Х	L
Н	Х	X	L

NOTES:

H = High voltage level

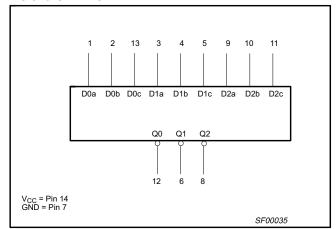
L = Low voltage level

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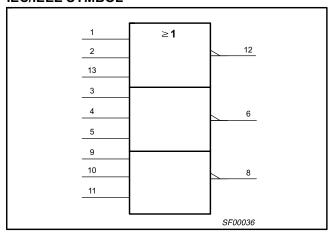
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LOGIC SYMBOL



IEC/IEEE SYMBOL



ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limit set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free air temperature range.)

SYMBOL	PARAMETER		RATING	UNIT
V _{CC}	Supply voltage		-0.5 to +7.0	V
V _{IN}	Input voltage		-0.5 to +7.0	V
I _{IN}	Input current		-30 to +5	mA
V _{OUT}	Voltage applied to output in high output state		–0.5 to V _{CC}	V
I _{OUT}	Current applied to output in low output state		40	mA
_	Operating free circumposeture range	Commercial range	0 to +70	°C
T _{amb}	Operating free air temperature range	Industrial range	-40 to +85	°C
T _{stg}	Storage temperature range		-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER			LIMITS		UNIT
			MIN	NOM	MAX	1
V _{CC}	Supply voltage		4.5	5.0	5.5	V
V _{IH}	High-level input voltage		2.0			V
V _{IL}	Low-level input voltage				0.8	V
I _{lk}	Input clamp current				-18	mA
I _{OH}	High-level output current				-1	mA
I _{OL}	Low-level output current				20	mA
T _{amb}	Operating free air temperature range	Commercial range	0		+70	°C
		Industrial range	-40		+85	°C

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DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	·	TEST CONDITIO	NS ¹		LIMITS		UNIT
					MIN	TYP ²	MAX	
V _{OH}	High-level output voltage		V _{CC} = MIN, V _{IL} = MAX	±10%V _{CC}	2.5			V
			V _{IH} = MIN, I _{OH} = MAX	±5%V _{CC}	2.7	3.4		V
V _{OL}	Low-level output voltage	V _{CC} = MIN, V _{IL} = MAX	±10%V _{CC}		0.30	0.50	V	
			V _{IH} = MIN, I _{OI} = MAX		0.30	0.50	V	
V_{IK}	Input clamp voltage	$V_{CC} = MIN, I_I = I_{IK}$			-0.73	-1.2	V	
I _I	Input current at maximum input vo	tage	$V_{CC} = MAX, V_I = 7.0V$			100	μΑ	
I _{IH}	High-level input current		V_{CC} = MAX, V_I = 2.7V				20	μΑ
I _{IL}	Low-level input current		V_{CC} = MAX, V_I = 0.5V				-0.6	mA
I _{OS}	Short-circuit output current ³		V _{CC} = MAX		-60		-150	mA
I _{CC}	Supply current (total)	I _{CCH}	V _{CC} = MAX	V _{IN} = GND		4.0	5.5	mA
	I _{CCL}		V _{CC} = MAX	V _{IN} = 4.5V		8.5	12.0	mA

For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.

AC ELECTRICAL CHARACTERISTICS

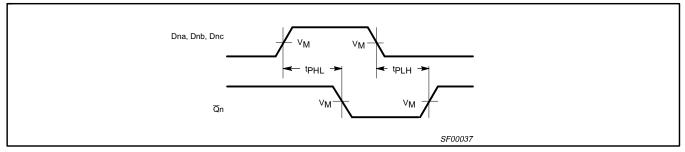
	MBOL PARAMETER			LIMITS						
SYMBOL		TEST CONDITION	V_{CC} = +5.0V T_{amb} = +25°C C_L = 50pF, R_L = 500 Ω			V _{CC} = +5. T _{amb} = 0°C C _L = 50pF,	c to +70°C	$V_{CC} = +5.$ $T_{amb} = -40^{\circ}$ $C_{L} = 50pF$	UNIT	
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t _{PLH} t _{PHL}	Propagation delay Dna, Dnb, Dnc to Qn	Waveform 1	2.0 1.0	3.5 2.5	5.0 4.5	1.5 1.0	5.5 4.5	1.0 1.0	7.0 5.5	ns

All typical values are at V_{CC} = 5V, T_{amb} = 25°C. Not more than one output should be shorted at a time. For testing I_{OS} , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

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AC WAVEFORMS

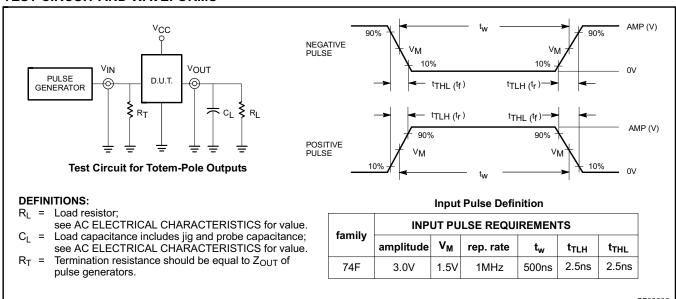


Waveform 1. Propagation delay for inverting outputs

NOTE:

For all waveforms, $V_M = 1.5V$.

TEST CIRCUIT AND WAVEFORMS



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SF00006

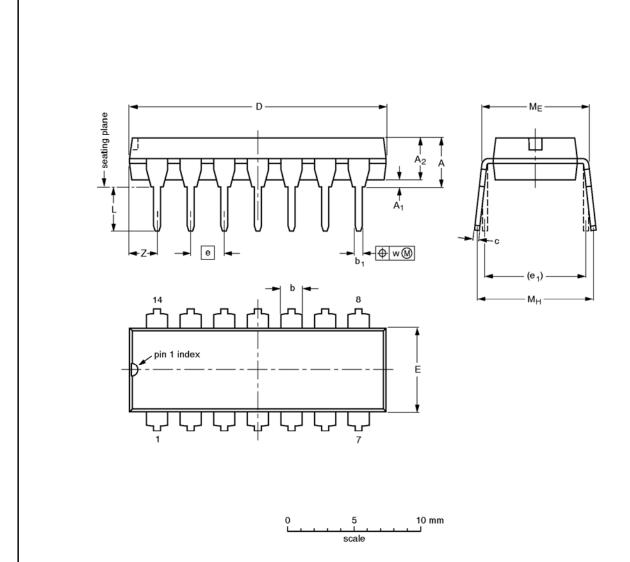
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DIP14: plastic dual in-line package; 14 leads (300 mil)

SOT27-1



DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	С	D ⁽¹⁾	E (1)	е	e ₁	L	ME	Мн	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.13	0.53 0.38	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.2
inches	0.17	0.020	0.13	0.068 0.044	0.021 0.015	0.014 0.009	0.77 0.73	0.26 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.087

Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE	OUTLINE REFERENCES VERSION IEC JEDEC EIAJ					ISSUE DATE	
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE	
SOT27-1	050G04	MO-001AA				92-11-17 95-03-11	

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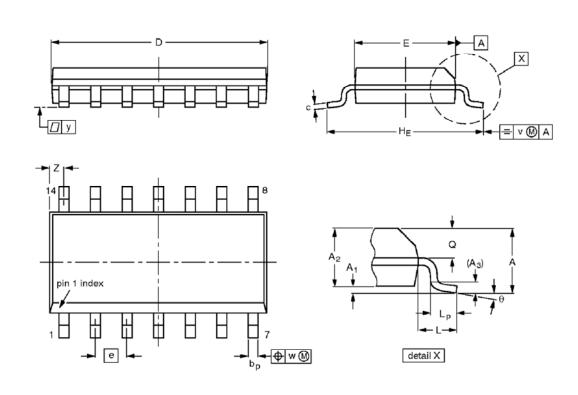
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SO14: plastic small outline package; 14 leads; body width 3.9 mm

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0 2.5 5 mm scale

DIMENSIONS (inch dimensions are derived from the original mm dimensions)

UNIT	A max.	A ₁	A ₂	A ₃	bр	С	D ⁽¹⁾	E ⁽¹⁾	e	HE	L	Lp	Q	v	w	у	Z ⁽¹⁾	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	8.75 8.55	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8°
inches	0.069	0.010 0.004	0.057 0.049	0.01		0.0100 0.0075	0.35 0.34	0.16 0.15	0.050	0.244 0.228	0.041	0.039 0.016	0.028 0.024	0.01	0.01	0.004	0.028 0.012	0°

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE			
VERSION	IEC	JEDEC	EIAJ		PROJECTION	1550E DATE	
SOT108-1	076E06S	MS-012AB				95-01-23 97-05-22	

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Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
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^[1] Please consult the most recently issued datasheet before initiating or completing a design.

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